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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): K. MITANI et al

Serial No. :

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For : GLASS SUBSTRATE FOR INFORMATION RECORDING MEDIA AND MANUFACTURING METHOD THEREOF

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Barbara Villani

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Asst. Commissioner for Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT

S I R :

Please amend the claims as follows:

11. **(amended)** A glass substrate for an information recording medium manufactured using the method claimed in claim 1, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

12. **(amended)** A glass substrate for an information recording medium manufactured using the method claimed in claim 1 , wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

Please add claims 13-30 as follows:

--13. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

14. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

15. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

16. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

17. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

18. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

19. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

20. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

21. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height EH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

22. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 2, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

23. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 3, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

24. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 4, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

25. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 5, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

26. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 6, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

27. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 7, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

28. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 8, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

29. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 9, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.

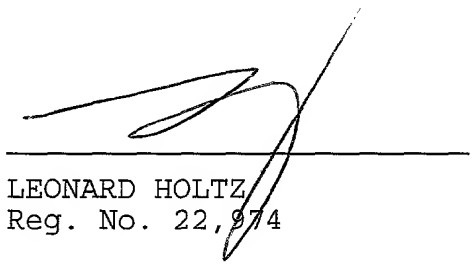
30. **(new)** A glass substrate for an information recording medium manufactured using the method claimed in claim 10, wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.--

REMARKS

A copy of the page of the original application containing the marked-up claims is attached hereto (we amended claims 11 and 12) with the amendments handwritten thereon.

The present amendment removes all multiple dependent claims without changing the scope of coverage.

Respectfully submitted,



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surface of the glass substrate that has been subjected to the surface scrubbing to chemical strengthening.

10. A method as claimed in claim 1, further comprising the step of subjecting texturing and chemical strengthening in this order to the at least one surface of the glass substrate before the surface scrubbing is carried out on the at least one surface of the glass substrate.

11. A glass substrate for an information recording medium manufactured using the method claimed in [any one claim 1 of claims 1 through 10], wherein a bearing height BH04 of at least one surface of the glass substrate at which a contact ratio is 0.4% as measured using an atomic force microscope is in a range of 2 to 7μm.

12. A glass substrate for an information recording medium manufactured using the method claimed in [any one claim 1 of claims 1 through 10], wherein a bearing height BH01 of at least one surface of the glass substrate at which a contact ratio is 0.1% as measured using an atomic force microscope is in a range of 2 to 10μm.